

FORM PTO 1449 (modified)			ATTY DOCKET NO. 03500.103410.	APPLICATION NO. 10/532,078			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPLICANT AKIRA UNNO, et al.				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			371(c) DATE: JAN 10 2007		GROUP April 21, 2005 2891		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MWS/		7,008,701	03/07/06	Notsu, et al.	428	641	
/MWS/		6,828,214	12/07/04	Notsu, et al.	438	455	
/MWS/		6,783,588	08/31/04	Aoto, et al.	117	4	
/MWS/		6,639,327	10/28/03	Momoi, et al.	257	913	
/MWS/		6,613,678	09/02/03	Sakaguchi, et al.	438	695	
/MWS/		6,593,211	07/15/03	Sato	438	455	
/MWS/		6,569,748	05/27/03	Sakaguchi, et al.	438	455	
/MWS/		6,506,665	01/14/03	Sato	438	458	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/MWS/		1 385 220	01/28/04	Europe			
/MWS/		1 006 152	06/07/00	Europe			
/MWS/		2004-165427	06/10/04	Japan			Abstract
/MWS/		2004-55654	02/19/04	Japan			Abstract
/MWS/		2001-94107	04/06/01	Japan			Abstract
/MWS/		2000-256527	09/19/00	Japan			Abstract
/MWS/		7-206599	08/08/95	Japan			Abstract
/MWS/		3-255669	11/14/91	Japan			Abstract
/MWS/		03/041185	05/15/03	PCT/WO			
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
/MWS/		A. R. Brown, et al., "A universal relation between conductivity and field-effect mobility in doped amorphous organic semiconductors", Synthetic Metals, Vol. 68, 1994, pp. 65-70.					
/MWS/		Y.-Y. Lin, et al., "Stacked Pentacene Layer Organic Thin-Film Transistors with Improved Characteristics", IEEE Electron Device Letters, Vol. 18, No. 12, December 1997, pp. 606-608.					
/MWS/		M. Yoshida, et al., "Surface Potential Control of an Insulator Layer for the High Performance Organic FET", Synthetic Metals, Vol. 137, 2003, pp. 967-968.					
EXAMINER	/Matthew Such/			DATE CONSIDERED	09/22/2007		

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>			ATTY DOCKET NO. 03500.103410.		APPLICATION NO. 10/532,078		
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MWS/		6,433,359	08/13/02	Kelley, et al.	257	40	
/MWS/		6,413,874	07/02/02	Sato	438	714	
/MWS/		6,407,367	06/18/02	Ito, et al.	219	390	
/MWS/		6,375,738	04/23/02	Sato	117	89	
/MWS/		6,335,269	01/01/02	Sato	438	509	
/MWS/		6,252,002	06/26/01	Yamada, et al.	525	228	
/MWS/		6,221,738	04/24/01	Sakaguchi, et al.	438	455	
/MWS/		6,171,982	01/09/01	Sato	438	795	
/MWS/		6,143,629	11/07/00	Sato	438	455	
/MWS/		6,143,628	11/07/00	Sato, et al.	438	455	
/MWS/		6,106,613	08/22/00	Sato, et al.	117	54	
/MWS/		5,970,361	10/19/99	Kumomi, et al.	438	409	
/MWS/		5,912,473	06/15/99	Wakita, et al.	257	40	
/MWS/		5,556,706	09/17/96	Wakita, et al.	438	421	
/MWS/		5,546,889	08/20/96	Wakita, et al.	117	84	
/MWS/		5,500,537	03/19/96	Tsumura, et al.	257	40	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
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